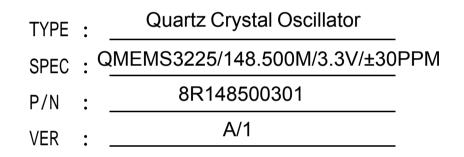


# 江苏浩都频率科技有限公司

JIANGSU HD-CRYSTAL TECHNOLOGY CO., LTD

# **Specifications For Product**





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## Specification Revision Record Sheet

Rev.	Revise page	Revise Contents	Date	Ref. No.	Reviser
A/0	N/A	Initial released	2018/3/30	N/A	吴佳斌
A/1	N/A	P/N revision	2020/1/1	N/A	吴佳斌

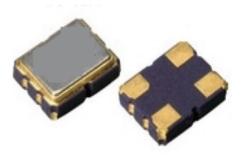
## 8R148500301

- 1. Scope:
- 1.1 This specification applies to the RoHS crystal oscillator with a frequency of 148.500 MHz which will be used in electronic equipment.
- 2. Construction:
- 2.1 Oscillators series: QMEMS3225 8R series
- 2.2 Package: SMD3.2×2.5

#### 3. Electrical Characteristics

3.1	Nominal Frequency:	148.500MHz
3.2	Frequency Stability:	±30ppm
o	incl. 25°C tolerance, tolerance over perating temperature range, input voltage hange, load change, 1 year aging)	
3.3	Aging:	±3ppm/year
3.4	Operating Temperature Range:	-40 to + 85°C
3.5	Storage Temperature Range:	-55 to + 125°C
3.6	Input Voltage (V <sub>DD</sub> ):	+3.3Vdc±10%
3.7	Input Current (I <sub>DD</sub> ):	36mA max
3.8	Output Waveform:	CMOS
3.9	Output Symmetry:	50±5%
3.10	Rise/Fall Time:	5ns max
3.11	Output Voltage V <sub>OL</sub> :	10%VDD
	V <sub>OH</sub> :	90%VDD
3.12	Output Load:	15pF
3.13	Output State Control:	Enable/disable
3.14	Start-up Time:	8ms max
3.15	Phase Jitter (rms):	1ps rms max 12kHz to 20MHz max
3.16	Oscillation mode:	Fundmental
0 47		

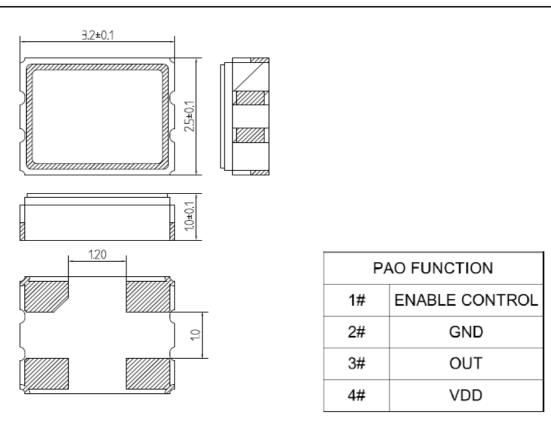
3.17 Others:Not recommended for safety applications



## **Reliability Specification**

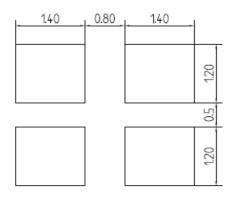
NO.	ITEM	SPECIFICATION	TEST METHOD
4.1	Temperature Cycle (GB/T 2423.22-2002, Method Nb)	Frequency change after test≤± 5ppm.	10 cycles from -55°C to 125°C. Measurement taken after DUT being left at room temperature for $24\pm 2$ hours.
4.2	Low Temperature Storage (GB/T 2423.1-2001, Method Aa)	Frequency change after test≤± 5ppm.	Spending 72 hrs at -55°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.3	High Temperature Storage (GB/T 2423.2-2001, Method Ba)	Frequency change after test≤± 5ppm.	Spending 72 hrs at 125°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.4	Humidity (GB/T 2423.3- 2006, Method Cab)	Frequency change after test≤± 5ppm.	Spending 96 hrs at 40 °C ± 3 °C, with 90± 3% R.H. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.5	Vibration(GB/T 2423.10- 1995, Method Fc)	Frequency change after test≤± 5ppm.	Apply 0.75mm vibration at sweep frequency $10\sim500$ Hz, for 2h. 10 cycles in each direction of 3 axis. Measurement taken after 1 hour.
4.6	Shock (GB/T 2423.5-1995, Method Ea)	Frequency change after test≤± 5ppm. No visible damages.	Peak 1000m/s2, normal width 6ms half sine wave form, 3.7m/s, 3 perpendicular axis of samples, 3 cycles / direction, total 18 cycles. Measurement taken after 1 hour.
4.7	Drop (GB/T 2423.8-1995, Method Ed)	Frequency change after test≤± 5ppm. No visible damages.	Free drop to the wooden plate from 1.0 m heights for 3 times.
4.8	Solderability (GB/T 2423.28-2005, Method Tc)	Terminals shall be covered more then 95% with solder.	In 245 $\pm$ 5 $^\circ\!\mathrm{C}$ solder bath for 2 $\pm$ 0.5 seconds. There is no need to do functioned test. 8-12X magnifier.
4.9	Terminal Strength (JIS-C- 6429 Method 1 & 2)	No visible damage	Mount on a glass-epoxy board (100x50x1.6mm), then bend to 2mm displacement (velocity 1mm/sec) and keep for 5 seconds. or pulling force 0.5 kg for at least 60 seconds.
4.10	Resistance to Soldering Heat (GB/T 2423.28-2005, Test Tb Method 1B)	Frequency change after test≤± 5ppm.	Passed through the re-flow oven under the following condition. Preheat to 150°C±5°C for 60 to 120sec,and peak 265°C±5°C for 10s±3sec.Measurement taken after DUT being left at room temperature for at 24±2 hours.
4.11	OTHERS		

### Package Outline Dimensions



Units:mm

### Suggested Pad Layout



Units:mm

